**FORM PTO-1449** 

## U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO.	APPLICATION 100/786,083		
1391.1056	Limesigned.		
FIRST NAMED INVENTOR			
Ching Y. Suen et al.			
FILING DATE	GROUP ART UNIT 2624		
February 26, 2004	U <del>nassig</del> ned		

## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

## **U.S. PATENT DOCUMENTS**

U.O. I ATENT BOOMILETTO							
EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE					•	
	AF						

## **FOREIGN PATENT DOCUMENTS**

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSI YES	ATION NO
/GD/	AG	5-12491	01/22/93	Japan			х	
	АН							
	Al							
	AJ							

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

/GD/	AK	Simon X. LIAO et al., "On Image Analysis by Moments," IEEE Trans. on PAMI, Vol. 18, No. 3, March 1996, pp. 254-266 (March 1996).
/GD/	AL	S. SATOH et al., "Evaluation of Two Neocognitron-type Models for Recognition of Rotated Patterns," ICONIP 2000, WBP-04 (2000), pp.295-299.
/GD/	AM	Q. XIE et al., "A Construction of Pattern Recognition System Invariant to Translation, Scale-Change and Rotation Transformation of Patterns," Vol. 27, No. 10, pp. 1167-1174 (1991).
/GD/	AN	H. Hase et al., "Alignment of Free Layout Color Texts for Character Recognition," Proceeding of the Sixth International Conference on Document Analysis and Recognition, September 10-13, 2001, pp. 932-936 (Sept. 2001).
/GD/	AO	Hiroshi MURASE et al., "Three-dimensional object recognition using two-dimensional collation - parametric Eigen space techniques, IECE Trans. vol. J77-D-II, no. 11, Nov. 1994, pp.2179-2187 (Nov. 1994).

EXAMINER /Gregory Desire/	DATE CONSIDERED	05/14/2007			
EVANUED. In the life of the configuration of the configuration is in conformance with MPEP 609. Draw line through citation if not in conformance					

and not considered. Include copy of this form with next communication to applicant.